

COPPERLIT (Copper Data Center Database (CDC))



Subject Coverage

Major areas of coverage include:

- Competitive materials
- Composites
- Copper compounds
- Corrosion and oxidation
- Energy
- Extractive metallurgy
- Fabrication
- Insulation
- Joining
- Melting and casting
- Physical metallurgy
- Pollution control
- Powder metallurgy
- Properties
- Superconductivity

File Type

Bibliographic

Features

Thesaurus	None				
Alerts (SDIs)	Monthly				
CAS Registry Numbers®	<input type="checkbox"/>	Page Images	<input type="checkbox"/>	STN AnaVist	<input type="checkbox"/>
Keep & Share	<input checked="" type="checkbox"/>	SLART	<input checked="" type="checkbox"/>	STN Easy	<input checked="" type="checkbox"/>
Learning Database	<input type="checkbox"/>	Structures	<input type="checkbox"/>	STN Viewer	<input type="checkbox"/>

Record Content

Bibliographic information, indexing, and mostly an abstract

File Size

81,020 records (03/11)

Coverage

1965-present, including 5,582 documents published between 1863 and 1964

Updates

Monthly

Language

English

Database Producer

Cambridge Scientific Abstracts
7200 Wisconsin Avenue
Bethesda, MD, 20814
U.S.A.
Phone: +1 301-961-6700
Fax: +1 301-961-6720
E-mail: support@csa.com

Copyright Holder
Copper Development Association Inc. (CDA)

Database Supplier FIZ Karlsruhe
STN Europe
P.O. Box 2465
76012 Karlsruhe
Germany
Phone: +49-7247-808-555
Fax: +49-7247-808-259
E-mail: helpdesk@fiz-karlsruhe.de

- Sources**
- Journals
 - Books
 - Conferences
-

- User Aids**
- Online Helps (HELP DIRECTORY lists all help messages available)
 - STNGUIDE
-

- Clusters**
- ALLBIB
 - AUTHORS
 - CHEMISTRY
 - COMPANIES
 - CORPSOURCE
 - CSAALL
 - ENGINEERING
 - MATERIAS
 - METALS
- [STN Database Clusters](#) information (PDF).
-

Pricing See the [STN Price List](#) or enter HELP COST at an arrow prompt.

Search and Display Field Codes

Fields that allow left truncation are indicated by an asterisk (*).

General Search Fields

Search Field Name	Search Code	Search Examples	Display Codes
Basic Index* (contains single words from the abstract (AB), title (TI), corporate name (CO) and controlled term (CT) fields)	None or /BI	S LIQUID COPPER S NEUTRON(L)DIFFRACTION S SCR PROCESS S ?RADIATION?	TI, AB, CO, CT
Accession Number	/AN	S 800080/AN	AN
Author	/AU	S DANG C/AU	AU
Classification Code	/CC	S 11/CC	CC
Classification Code (code and text) (1)		S COPPER COMPOUNDS/CC	
Controlled Term	/CT	S MECHANICAL CLEANING/CT	CT
Controlled Word	/CW	S ACOUSTIC EMISSION/CW	CT
Corporate Name (1,2)	/CO	S NASA CENTER/CO	CO
Corporate Source (author's affiliation) (1)	/CS	S UNIV CALIFORNIA/CS	CS
Country of Publication (ISO code and text) (2)	/CY	S GB/CY S UNITED KINGDOM/CY	CY
Document Type (code and text)	/DT	S L1 AND J/DT	DT
E-mail Address (1,4)	(or /TC) /EML	S JOURNAL/DT S AIP ORG/EML	AU, EML, SO, PB
Field Availability	/FA	S AB/FA	not displayed
International Standard (Document) Number (contains ISSN and ISBN)	/ISN	S 0142-727X/ISN S 0-87170-627-X/ISN	ISN, SO
Journal Title (contains full and abbreviated titles) (2)	/JT	S MATERIALS LETTERS/JT	JT, SO, JTA, JTF
Language (ISO code and text)	/LA	S EN/LA S ENGLISH/LA	LA
Meeting Date (2,3)	/MD	S MD=26 AUG 1999	MD, SO
Meeting Location (1,2)	/ML	S BIRMINGHAM/ML	ML, SO
Meeting Title (2)	/MT	S ANNUAL TECHNICAL MEETING/MT	MT, SO
Meeting Year (2,3)	/MY	S 1999-2000/MY	MY, SO
Note	/NTE	S TRANSLATIONS/NTE	NTE
Number of Report (2)	/NR	S CU-639/NR	NR
Publication Date (3)	/PD	S PD=FEB-MAR 2000	PD, SO
Publication Year (3)	/PY	S PY>1999	PY, SO
Publisher (1,2)	/PB	S ASM INTERNATIONAL/PB	PB, SO
Reference Count (2,3)	/REC (or /RE.CNT)	S REC=<10	REC, SO
Source (contains journal titles, collation and pagination information, publisher information, meeting information, ISSN, ISBN, e-mail address, and URL)	/SO	S (CONDENSED MATTER AND 12)/SO S 0953 8984/SO S COUNCIL OF CANADA/SO S CONFERENCE ON TEXTURES/SO	SO
Title	/TI	S NANOCRYSTALLINE/TI	TI
Uniform Resource Locator (1,4)	/URL	S SPRINGER/URL	URL, SO
Update Date (3)	/UP (or /ED)	S UP=OCT 2001	UP
Word Count, Title (3)	/WC.T	S WC.T=5	WC.T

Search and Display Field Codes (cont'd)

- (1) Search with implied (S) proximity is available in this field.
 (2) Field available since May 1999.
 (3) Numeric search field that may be searched with numeric operators or ranges.
 (4) Field available since April 2005.

DISPLAY and PRINT Formats

Any combination of formats may be used to display or print answers. Multiple codes must be separated by spaces or commas, e.g., D L1 1-5 TI AU. The fields are displayed or printed in the order requested.

Hit-term highlighting is available for all fields. Highlighting must be ON during SEARCH to use the HIT, KWIC, and OCC formats.

Format	Content	Examples
AB	Abstract	D TI AB
AN	Accession Number	D 1-5 AN
AU	Author (includes CS)	D AU TI
CC	Classification Code	D CC
CO	Corporate Name	
CS	Corporate Source	D CS
CT	Controlled Term	D CT
CY	Country (of Publication)	D CY
DT (TC)	Document Type	D DT
EML (1)	E-mail Address	D EML
ISN (1)	International Standard (Document) Number	D ISN
JT (1)	Journal Title	D JT
JTA (1)	Journal Title, Abbreviated	D JTA
JTF (1)	Journal Title, Full	D JTF
LA	Language	D LA TI
MD (1)	Meeting Date	D MD
ML (1)	Meeting Location	D ML
MT (1)	Meeting Title	D MT
MY (1)	Meeting Year	D MY
NR	Number of Report	D NR
NTE	Note	D NTE
PB (1)	Publisher	D PB
PD (1)	Publication Date	D PD
PY (1)	Publication Year	D PY
REC (RE.CNT) (1)	Reference Count	D REC
SO	Source	D SO
TI	Title	D TI 1-3
UP (ED) (1)	Update Date	D UP
URL (1)	Uniform Resource Locator	D URL
WC.T (1)	Word Count, Title	D WC.T
ABS	AN, AB	D ABS
ALL	AN, TI, AU, CS, NR, SO, DT, CY, LA, NTE, AB, CC, CT, CO	D ALL
DALL	ALL, with delimiter for post processing	D DALL
IALL	ALL, indented with text labels	D IALL
BIB	AN, TI, AU, CS, NR, SO, DT, CY, LA, NTE (BIB is the default)	D 8 BIB
IBIB	BIB, indented with text labels	D IBIB
IND	AN, CC, CT, CO	D IND
SCAN (2)	TI, CT (random display without answer numbers)	D SCAN
TRIAL (TRI, SAM, SAMPLE, FREE)	AN, TI, CT	D TRI

DISPLAY and PRINT Formats (cont'd)

Format	Content	Examples
HIT KWIC OCC	Hit term(s) and field(s) Up to 50 words before and after hit term(s) (KeyWord-In-Context) Number of occurrences of hit term(s) and field(s) in which they occur	D HIT D KWIC D OCC

(1) Custom display only.

(2) SCAN must be specified on the command line, i.e., D SCAN or DISPLAY SCAN.

SELECT, ANALYZE, and SORT Fields

The SELECT command is used to create E-numbers containing terms taken from the specified field in an answer set.

The ANALYZE command is used to create an L-number containing terms taken from the specified field in an answer set.

The SORT command is used to rearrange the search results in either alphabetic or numeric order of the specified field(s).

Field Name	Field Code	ANALYZE/ SELECT (1)	SORT
Abstract	AB	Y (2)	N
Accession Number	AN	Y	N
Author	AU	Y	Y
Citation	CIT (RE)	Y (3,4)	N
Classification Code	CC	Y	Y
Controlled Term	CT	Y	N
Corporate Name	CO	Y	Y
Corporate Source	CS	Y	Y
Document Type	DT (TC)	Y	Y
E-mail Address	EML	Y	Y
International Standard (Document) Number	ISN	Y (5)	Y
International Standard Book Number	ISBN	N	Y
International Standard Serial Number	ISSN	N	Y
Journal Title	JT	Y	Y
Journal Title, Abbreviated	JTA	Y	Y
Journal Title, Full	JTF	Y	Y
Language	LA	Y	Y
Meeting Date	MD	Y	Y
Meeting Location	ML	Y	Y
Meeting Title	MT	Y	Y
Meeting Year	MY	Y	Y
Note	NTE	Y	Y
Number of Report	NR	Y	Y
Occurrence Count of Hit Terms	OCC	N	Y
Other Source	OS	Y	Y
Publication Date	PD	Y	Y
Publication Year	PY	Y	Y
Publisher	PB	Y	Y
Source	SO	Y (6)	Y
Title	TI	Y (default)	Y
Uniform Resource Locator	URL	Y	Y
Update Date	UP (ED)	Y	Y
Word Count, Title	WC.T	Y	Y

COPPERLIT

SELECT, ANALYZE, and SORT Fields (cont'd)

- (1) HIT may be used to restrict terms extracted to terms that match the search expression used to create the answer set, e.g., SEL HIT TI.
- (2) Appends /BI to the terms created by SELECT.
- (3) SELECT or ANALYZE CIT allows you to extract the reference from the source documents in this file and have them automatically converted to a citation format for searching in the SCISEARCH file. SEL or ANALYZE CIT extracts first author, publication year, volume, first page, with a truncation symbol and with /RE appended to the terms created by SELECT.
- (4) SELECT HIT or ANALYZE HIT are not valid with this field.
- (5) Selects or analyzes ISSN, and ISBN with /ISN appended to the terms created by SELECT.
- (6) Selects or analyzes ISSN, and ISBN with /SO appended to the terms created by SELECT.

Sample Record**DISPLAY ALL OF JOURNAL**

AN 812549 COPPERLIT
 TI Mechanism of Ni Film CVD with a Ni(ktfaa)₂ Precursor on a Copper Substrate
 AU Bakovets, Vladimir V (Nikolaev Institute of Inorganic Chemistry, SB RAS, 630090 Novosibirsk, Russia); Mitkin, Valentin N; Gelfond, Nikolai V
 mailto: became@che.nsk.su
 SO Chemical Vapor Deposition, 11, (2), (Feb. 2005), 112-117,
 Photomicrographs, Numerical Data, Graphs, Spectra, 29 reference(s)
 Published by: Wiley-VCH Verlag GmbH, P.O. Box 10 11 61, Weinheim,
 D-69451, Germany
 mailto: cs-journals@wiley.co.uk
 Url: <http://www.interscience.wiley.com>
 ISSN: 0948-1907
 DT Journal
 CY Germany, Federal Republic of
 LA English
 AB Metallization is one of the most important stages of electronic device production. Thin films of Ni are deposited on Cu substrates by CVD in the temperature region 250-350 deg C using a Ni(ktfaa)₂ chelate precursor. At about 300 deg C chelate pyrolysis takes place on the surface of Cu and in the gas phase. This temperature is the highest limit for CVD nickel films. Thermal analysis indicates that in the presence of hydrogen the CVD for nickel films might be decreased to 213 deg C. In the temperature region 250-300 deg C the Ni films are continuous, with good adhesion to a Cu substrate.
 CC 4 Surface Treatment
 CT Chemical vapor deposition; Nickel; Thin films; Metallizing; Copper; Precursors; COPPER (PURE); CHEMICAL VAPOR DEPOSITION; NICKEL (PURE); ELEVATED TEMPERATURE (100-250C); ELEVATED TEMPERATURE (250-400C); CHELATES

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 STN North America
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 Columbus, Ohio 43210-0012 U.S.A.

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 614-447-3700 (worldwide)
 Fax: 614-447-3751
 E-mail: help@cas.org
 Internet: www.cas.org

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 P.O. Box 2465
 76012 Karlsruhe
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 Fax: +49-7247-808-259
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 Internet: www.stn-international.com

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 International Chemical Information)
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